

<b>Notice of References Cited</b>	Application/Control No. 10/723,591	Applicant(s)/Patent Under Reexamination CHUAH ET AL.	
	Examiner JOHN J. LEE	Art Unit 2618	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0191562	12-2002	Kumaki et al.	370/331
*	B	US-2003/0153346	08-2003	Kim et al.	455/522
*	C	US-2004/0131026	07-2004	Kim et al.	370/328
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	K	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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